## Notice of References Cited Application/Control No. 10/770,245 Examiner David S. Blum Applicant(s)/Patent Under Reexamination YANG ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,479,348 B1	11-2002	Kamal et al.	438/258
	В	US-5,418,176 A	05-1995	Yang et al.	438/262
	С	US-6,037,227 A	03-2000	Hong, Gary	438/276
	D	US-6,653,191 B1	11-2003	Yang et al.	438/258
	Е	US-6,653,190 B1	11-2003	Yang et al.	438/258
	F	US-			
	G	US-			·
	Н	US-			
	1	US-		·	
	J	US-			
	К	US-			
	L	US-			
	М	US- <sub>o</sub>			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	Stanley Wolf SILICON PROCESSING FOR THE VSLI ERA Vol. 1 1986 Lattice Press pages 298-299					
	٧	Dielectric Materials, Google search, permittivity, 5/25/05					
	w						
	х						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.